Additive Manufacturing Packaging Applications and Growth Needs for Heterogeneous Integration Impact

Kris Erickson

Research Manager, Materials Development



Agenda

- 1. Additive Manufactured Electronics (AME) & Heterogenous Integration (HI)
- 2. AME Benefits
- 3. AME for XR
- 4. AME Manufacturing & Materials
- 5. AME Advances & Applications towards Future Electronics & HI
- 6. AME Growth Needs

Large collaborative team for creating full content!

Finalizing as a Chapter within HIR 2024

Technical Working Group Contributing Members



Kris Erickson (Meta)



Eric Dede (Toyota Research Institute of North America)



Jarrid Wittkopf (HP Labs)



Christine Kallmayer (Fraunhofer IZM)

HETEROGENEOUS
INTEGRATION ROADMAP



Dishit Parekh (Intel)



Alex Cook (Nextflex)



Jeroen van den Brand (Holst Center)



Mike Newton (Sciperio)



Annette Teng (Promex)



David Bowen (Laboratory for Physical Sciences)



Mark Poliks (Binghamton U)



Girish Wable (Jabil)



Martin Hedges (Neotech AMT)



Dean Turnbaugh (NTV)



David Weins (Siemens)



Richard Neill (ADVPES)



David Rosenfeld (Celanese)



Markus Scheibel (Heraeus)

Additively Manufactured Electronics (AME)

AME = Printed Conductor + (Printed/Existing) Dielectric + (optional) Additional Processes

AME Deposition

Dot Deposition Line Deposition **Area Deposition**

Direct-write & Conformal**

Dispensing & Extrusion Print

Non-contact Jetting Methods

Inkjet Print
Aerosol Print
Electrohydrodynamic Print
Piezo-Valve Jetting
Laser Induced Forward Transfer (LIFT)

** can deposition on 2D or 3D substrate

3D Print Methods

Fused Deposition Modeling SLA (Stereolithography) 2-photon SLA Digital Light Processing (DLP) Powder Bed Fusion

Contact 2D Print Methods*

Screen/Stencil Print Gravure Print Flexographic Print

* 2D only substrate

Additively Manufactured Electronics (AME)

Structural Electronics

Pick & Place Laser Direct Structuring (LDS) Electroplating

In-Mold Electronics

Pick & Place Thermoforming

Flexible Hybrid Electronics (FHE)

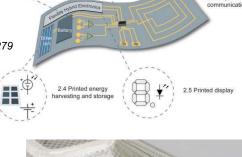
Pick & Place Solder
Deposition
Lithographically Defined
Features
Over-molding

Additional Supporting Processes

Pick & Place (Si, passives, etc.)
Curing/Sintering
3D Scanning
Metrology
Subtractive (Laser, Milling)

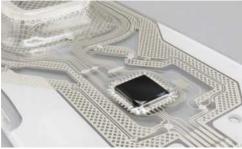


DOI: 10.1002/adma.201905279



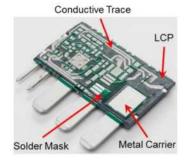
In-Mold Electronics

Project "Origami", 02/2018 - 01/2021, Innovations with Organic 3D Electronics. #thanks & with permissions from @Christine Kallmayer and Fraunhofer IZM

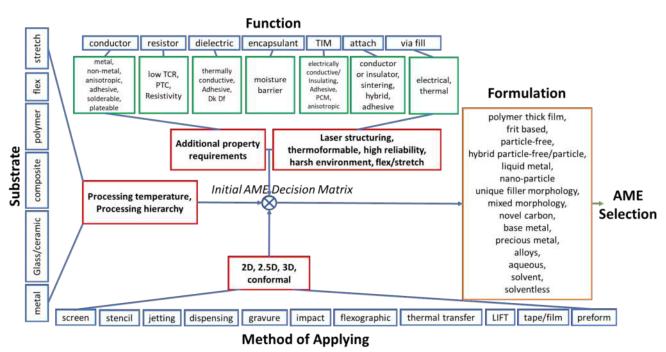


Structural Electronics

DOI: 10.1109/MID50463.2021.9361621



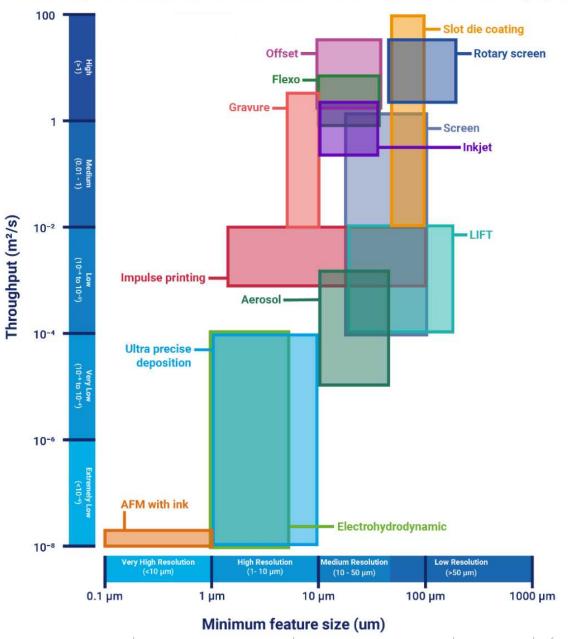
AME Considerations



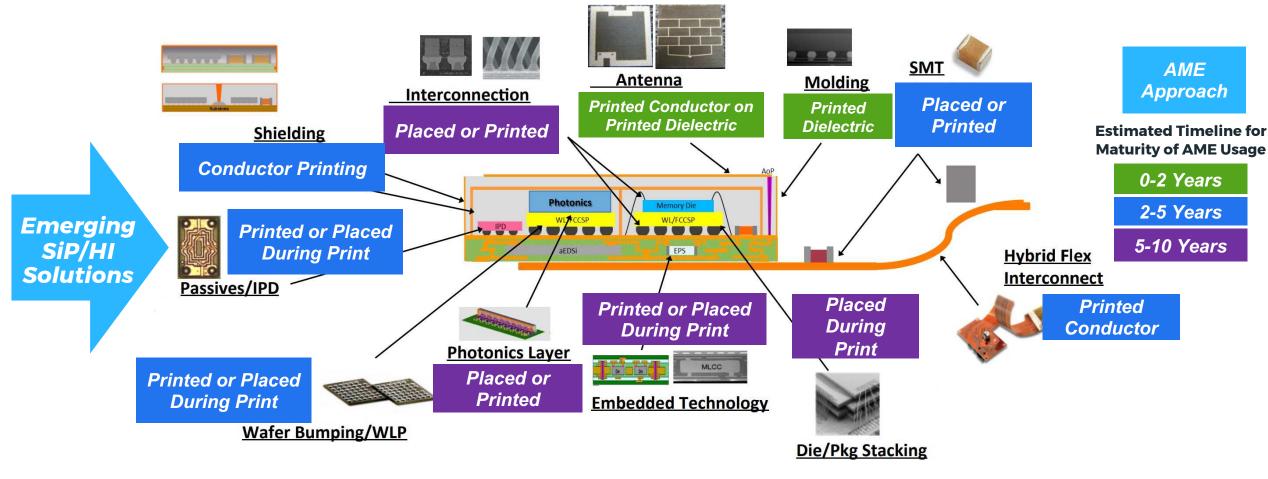
#thanks to Dave Rosenfeld, Celanese, and AME for HIR group

#thanks and with permissions from Max DePhillips, IDTechEx

Printing Methods for Electronics: Resolution vs Throughput



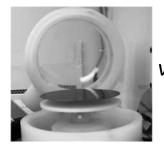
AME for Heterogenous Integration (HI)



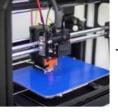
[HIR 2021 version (eps.ieee.org/hir), Ch. 8, Single and Multichip Integration] **In-progress** 2024 on HIR Chapter on AME

AME Benefits

Material efficiency



VS

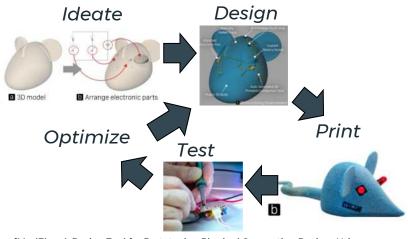


+

[https://https://commons.wikimedia.org/wiki]

[https://commons.wikimedia.org/wiki]

Design Freedom & Rapid Prototyping



[ModElec: A Design Tool for Prototyping Physical Computing Devices Using Conductive 3D Printing, L He, et al - Proceedings of the ACM on Interactive, 2021]

Simplified Manufacturing



VS.*



Litho Process Inkjet Process 1) Wafer Cleaning Cleaning and Ink and Preparation 2) Wet/Dry oxidation 2) Wet/Dry oxidation Deposition 4) Photoresist Spin 3) Printing: the number of passes depends on the 5)Photoresist exposure and Development 6)Etching 7)Photoresist Material Oxide Mask Photoresist

Low-volume/ Individualized Designs



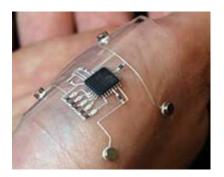
DOI 10.1186/s13104-015-0971-9

Novel Form Factors



DOI: 10.29026/oea.2018.170004

Flex/Wearable Devices



https://doi.org/10.1002/adma.201703817

AME for Extended Reality (XR)

EMG Wristband





https://tech.facebook.com/reality-labs/2021/3/inside-facebook-reality-labs-wrist-based-interaction-for-the-next-computing-platform/

Haptic Glove



https://about.fb.com/news/2021/11/reality-labs-haptic-gloves-research/





Fused Deposition Modeling for AME

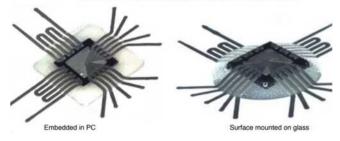
Down to ~100 micron features (~250 w/o micromachining), alternative conductor deposition methods typical, creating full 3D structures

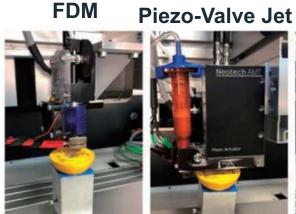
Neotech AMT

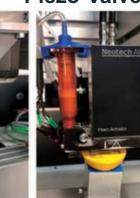
Combined, hybrid system

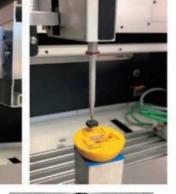
- FDM printing
- Direct write/Syringe
- 5-axis, Conformal Inkjet
- 5-axis, Conformal Aerosol Jet
- Laser sintering

QFN (Quad Flat No-lead) Microcontroller

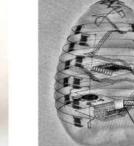






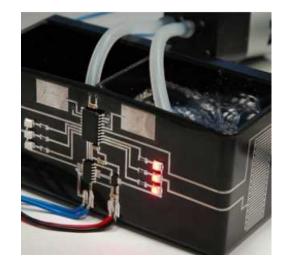


P&P







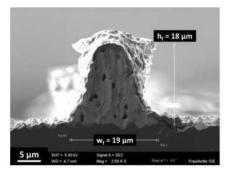


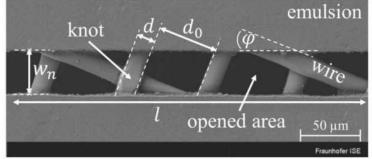
DOI: 10.29026/oea.2018.170004

Screen Print for AME

High speed, panel processing, typically to 50 micron features

Pushing Resolution for High Throughput Screen Print





https://doi.org/10.1038/s41598-021-83275-0

<= 20 micron feature demonstrations

Fraunhofer ISE, Asada Mesh

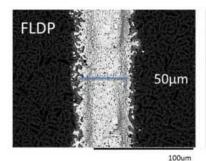
Continued Scaling for High Throughput

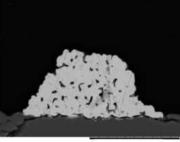
e.g. Applied Materials - Tempo Presto PE Screen Printer

High productivity 8,000 wafers/hr High Repeatability +/- 5 micron 3 Continuous line Modules - Load, Print, Unload/Dry/Clean Integrated: Profilometry, Alignment, Electrical Inspection

Solar Cell Metallization Applications







doi: 10.1016/j.egypro.2015.07.074

30

Direct Write Dispense for AME

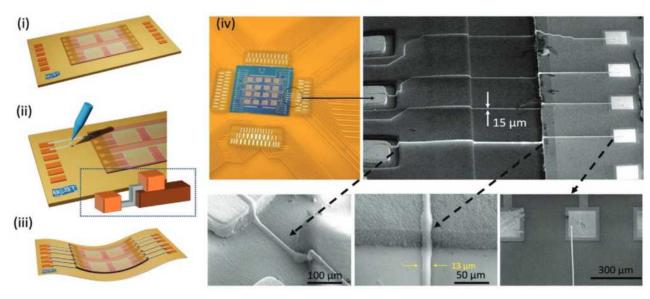
Down to ~15 micron features, high viscosity inks, patterning over topologies

nScrypt



[https://www.nscrypt.com/] #thanks and with permissions from Mike Newton, nScrypt

XTPL



Traces over substrate & chip steps Wire-bond alternative

DOI: 10.1002/aelm.202101029

Stereolithography (SLA) for AME

Down to ~100 micron features, alternative conductor deposition methods, creating full 3D structures

TNO Holst

SLA + Dispense



Self-harvesting NFC tag with temperature sensor

Modified SLA-Rake Process



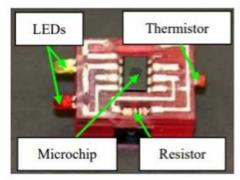
Fanout structure with 220 interconnects

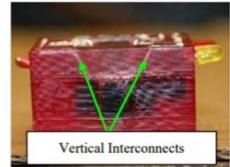
[https://executivereport.holstcentre.com/innovation-updates/enabling-technologies/3d-printed-electronics/]
#thanks and with permissions from Jeroen van den Brand and Holst Center

UT - El Paso

MacDonald Group - Keck Center

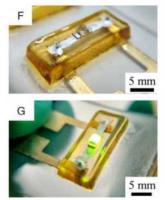
SLA, DW + Pick and Place Components



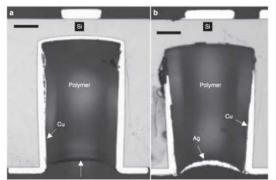


[D. Espalin, E. MacDonald. Int J Adv Manuf Technol 72, 963–978 (2014)]

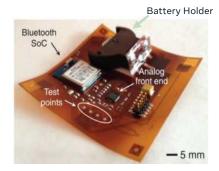
Inkjet for AME

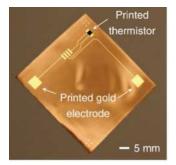


Inkjet Vertical Interconnects
DOI: 10.1002/adem.201900568



Inkjet filled & planarized TSV → increase I/O Density
doi.org/10.1038/micronano.2017.2





Wearable Health Monitoring - electrodes, thermistors

https://doi.org/10.1002/adfm.201603763

Example Application Areas

- Multilayer PCB-board applications
- Selective Solder masks for PCB
- Panel etching mask
- Encapsulation layers
- Dielectric, Conductor, Adhesive, and/or Mask Resist for Semiconductor Back-End Packaging
- Integratable with P&P methods
- Antenna Printing

Commercial Examples

NanoDimension

Dragonfly

Down to 75 micron features, 150 micron interconnects, min layer thickness 3 micron, multi-layer PCB builds

ChemCubed

ElectroJet

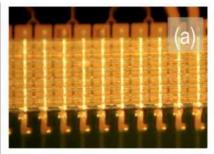
Suss PiXDRO

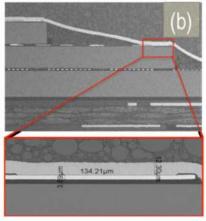
Down to 20 micron features

- Multiple commercial printheads
- In-line curing
- Precision substrate manipulation
- Automated Print Optimizations
- Gerber files → Inkjet Bitmap
- Material efficiency vs. standard coat + etch
- Up to 1200 wafers/hr (Jetx-P) or 80 panels/hr (Jetx-M)

Aerosol Printing for AME

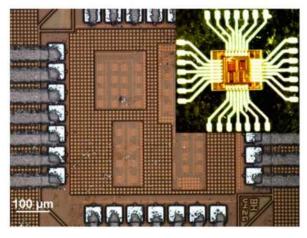
To 20 micron features, multi-materials, printing over topologies





Wire-bond Replacement

Hedges, Martin, and Aaron Borras Marin. "3D aerosol jet printing-adding electronics functionality to RP/RM." DDMC 2012 conference. 2012.



Print on un-Packaged Bare-die

Additional Applications

- High Frequency RF Interconnects
- Printed RDLs
- Package-level Shielding
- Printed Antennas

Commercial Examples

Optomec

Aerosol Jet 5X 3D Printer

IDS

NanoJet Systems

Electrohydrodynamic Jet for AME

High Resolution (at or below 1 micron features), wide ink viscosity range

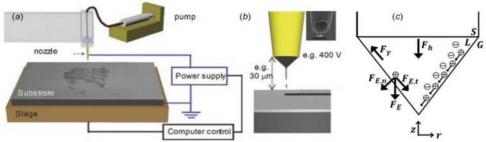
Commercial Examples

Super InkJet

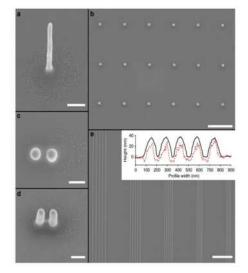
1 micron line/space

Scrona

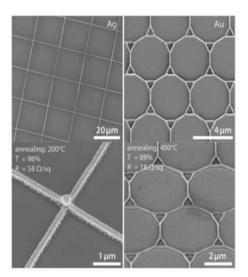
Multi-Nozzle, Annular Anode, down to 500 nm features, up to 10K cP inks



DOI: 10.1115/1.4041934

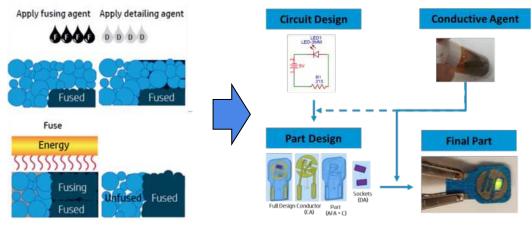


DOI: 10.1038/ncomms1891

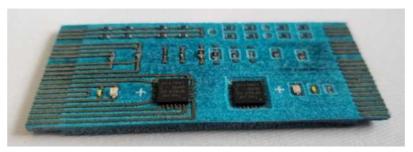


https://doi.org/10.1515/ntrev-2021-0073

Powder Bed Fusion for AME



[Techblick.com: **HP | 3D Printing of Electronics using Multi Jet Fusion]** #thanks and with permissions from Jarrid Wittkopf, HP Inc.



[Techblick.com: **HP | 3D Printing of Electronics using Multi Jet Fusion]** #thanks and with permissions from Jarrid Wittkopf, HP Inc.



[L. He, J. Wittkopf. Proc. ACM Interact. Mob. Wearable Ubiquitous Technol., Vol.5, No.4, Article159]

AME Advances Materials

FORM

Highly tailored per manufacturing approach



[https://www.shutterstock.com/] **Filaments FDM**



Photo-resins SLA, DLP



Films/Sheets Screen, Stencil, Gravure, Flexo

[https://www.shutterstock.com/]

DOI: 10.1007/s11665-014-1166-6

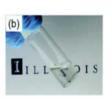
Nano/Micro-particle

FUNCTION

Conductors

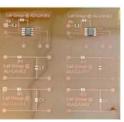
Silver-based

Traces, Interconnects, Vias, Antenna



DOI: 10.1039/c9tc05463d **Metal Salt**

Copper-based



DOI:10.1109/iTherm5 4085.2022.9899673

Flex-Stretch

Micron-Ag + Elastomer



doi.org/10.1002/admt.202000070 Liquid-Metal based



[https://www.shutterstock.com/] **Powders Powder Bed Fusion**



Inks Inkiet, Aerosol, EHD



Pastes Dispense, Screen, Stencil, Gravure, Flexo, Piezo-Valve

Dielectrics

Substrate, Packaging, Shielding, Capacitors

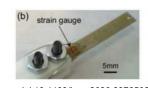
Flex/Stretch Substrates PET, TPUs, Silicones, Beyolux, etc.



doi:10.1021/acsnano.8b06464

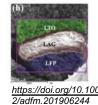
Specialized

Sensors, Resistive, Batteries, Optical, etc.



doi:10.1109/jsen.2020.2976508

Force Sensors



Batteries

AME Advances Manufacturing Integration & Productivity

Manufacturing Integration

Fraunhofer IPA - Next Factory

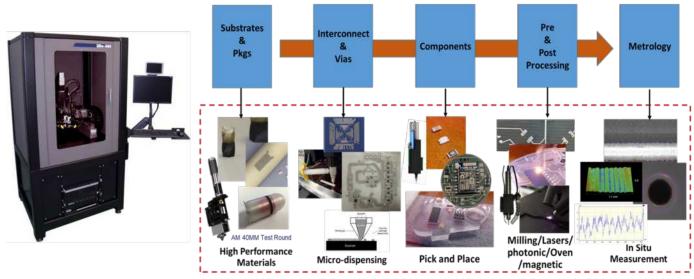
IJ + Cure/Sinter + Planarize + P&P/Assembly + Measurement/Inspect 100X100X50 mm build area; 10 micron layers, 150/250 micron l/s



[https://doi.org/10.1016/j.microrel.2018.04.008]

nScrypt

FDM + DW + P&P + Milling + Curing + Measurement



#thanks & with permissions from Mike Newton & nScrypt

Integration & Productivity

Screen Print

Up to 8K Wafers/hr Tempo Presto PE Screen Printer **Integrated** Profilometry, Alignment, Electrical Inspection, Wafer Load/Unload/Clean

Inkjet Print

Up to 1.2K Wafers/hr Suss PiXDRO **Integrated** Curing, Alignment

AME HI Applications Flex Use-case

#thanks and with permissions from Girish Wable, Jabil

RIGID PCBA



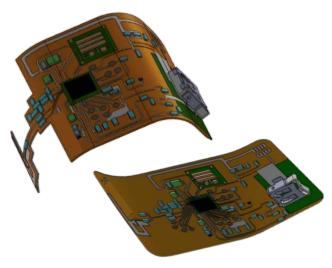
Board: Rigid FR4
Subtractive process
Copper traces

Weight (board): 17 grams

Assembly Temperature - 220 - 250 deg c

Cost: Baseline PCF - Baseline

RIGID-FLEX or FLEX PCBA



Flexible Polyimide Substrate
Subtractive process
Copper traces

Weight: 6 grams

Assembly Temperature - 220 - 250 deg c

Cost: Higher PCF - Baseline

FLEXIBLE HYBRID ELECTRONICS



Flexible Plastic Substrates
Printing (additive) process
Silver/Copper traces, Sensors

Weight: 2 grams

Assembly Temperature – 120 deg c

Cost*
Lower compared to Rigid Flex or Flex
PCF – Significantly Better*

* - more data needed

AME HI Applications Wearable Use-case



VALUE TRANSFORMATION

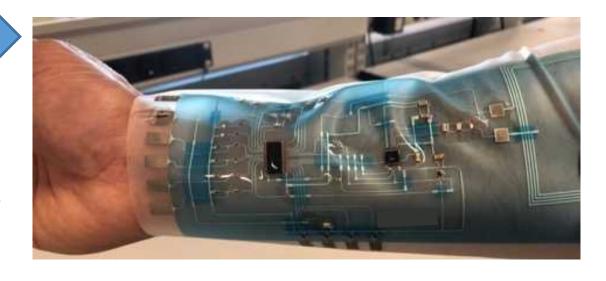
FLEXIBLE BENDABLE CONFORMAL

STRETCHABLE LIGHT TWISTABLE

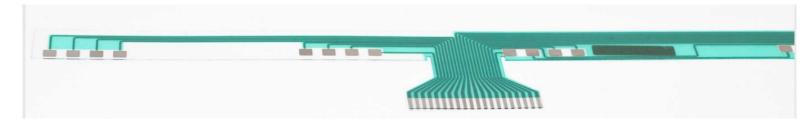
THIN DIRECT-DEPOSITED 3D

COST BENEFITS

BOM CONSOLIDATION
ASSEMBLY INTEGRATION

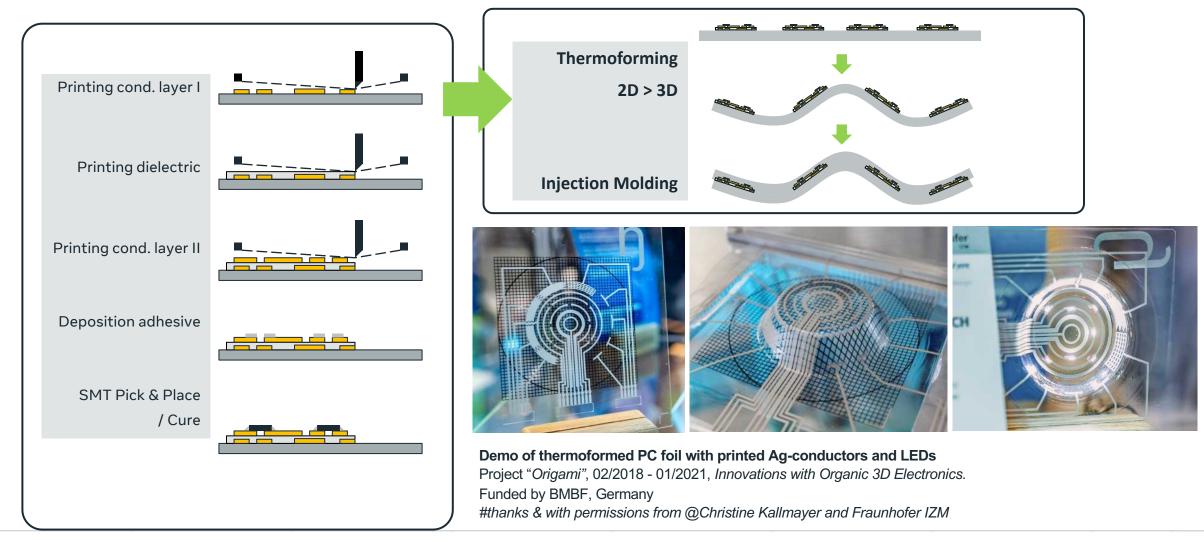






#thanks and with permissions from Girish Wable, Jabil

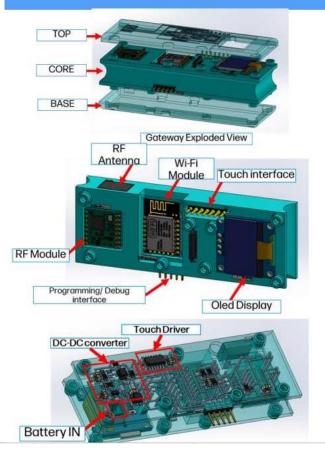
AME HI Applications Structural Electronics



Benefits Leveraging Design Freedom

AME HI Applications 3DPE Demonstrator

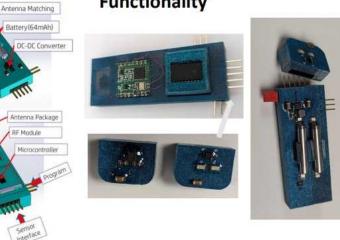
MJF 3DPE Demonstrator: Driving Device Complexity



130 different nodes 47 signals



Modularity in Design to Increase Functionality



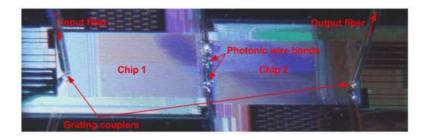
Gateway Node Sensor System Block Diagram



AME HI Applications Optical Wirebond

Specific Unmet HI Need

Interconnection Between Optical Chips & Output Fibers

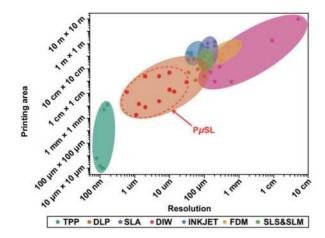


DOI 10.1364/OE.20.017667

Ultra-high Resolution 2-photon AME

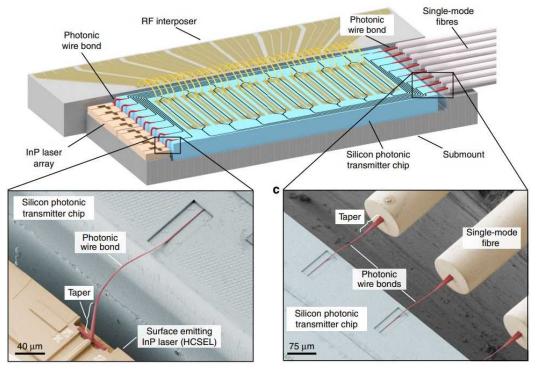
TPP - Two-Photon Polymerization

DOI 10.1088/2631-7990/ab8d9a



Unique Solution Space

Index Matched Photo-resin Automated Fabrication, Low losses, Passing Reliability Testing 400-700 GB/s Data Rate Demonstrations



Photonic Wire-bond doi.org/10.1038/s41377-020-0272-5

Benefits Leveraging

Unique Need + Unique Solution

AME HI Applications RF Structures

High performance monolithic microwave integrated circuit

Inkjet printed FSS & Cavity Board SLA Printed Encapsulant MMICs and Inkjet printed Gap Fill & RF Interconnect Frequency (GHz)

[M. Tentzeris, et al. IEEE Trans Microwave Theory Tech., 2020, 68, 2716-2724]

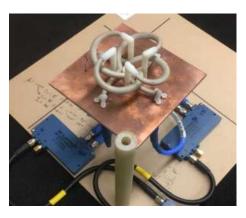
Inkjet & 3D Printed Broadband on-package Antenna





DOI 10.1109/ECTC.2018.00041

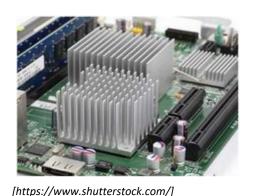
Fully 3D Antenna Geometries



DOI: 10.1109/ACCESS.2022.3202536

AME HI Applications Thermal

Air Cooled Heat Sinks



Current



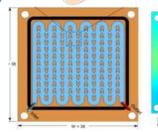


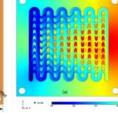
[Lazarov BS, Alexandersen J. Appl Energy. 2018;226(February): 330-339]

AM Thermal

Liquid Cooled Heat Sinks







Current

AM Thermal

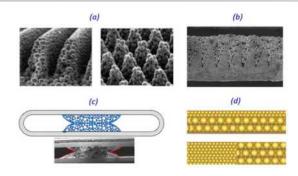
[Al-Neama AF, Thompson HM. Int J Heat Mass Transf. 2018;120:1213-1228]

Two Phase Convective Cooling

Current



[DOI: <u>10.1109/ITHERM.2006.1645335</u>]



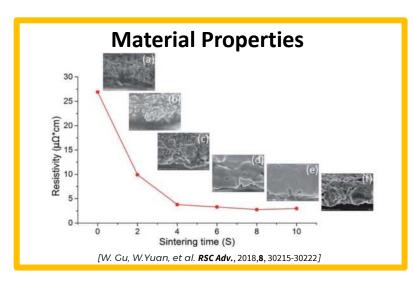
AM Thermal

[Jafari D, Wits. Renew Sustain Energy Rev. 2018; 91(April 2017):420-442]

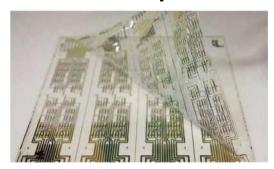
Benefits Leveraging

3D & Design Freedom

AME Growth Needs



Productivity & Yield



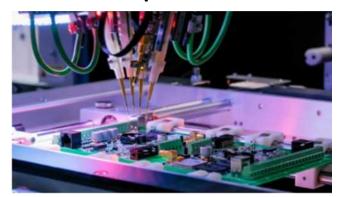
[https://commons.wikimedia.org/wiki]

Product-Level Reliability



[https://commons.wikimedia.org/wiki]

Automated Inspection & Correction



[https://www.shutterstock.com/image-photo]

Design Tools



[https://www.shutterstock.com/image-photo]

Integrated Manufacturing



Leveraging CapEx Investment & Adaptability to Current tooling

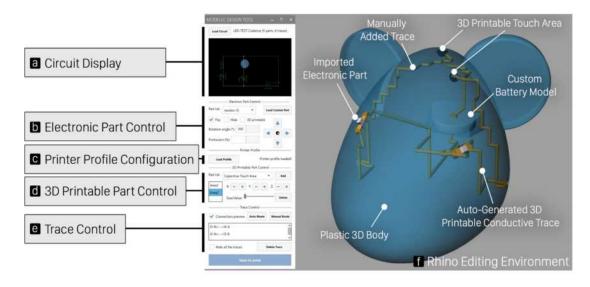
- Panel Sizes
- Planarity
- Alignment
- Form Factor
- Thermal Processes

[https://www.microwavejournal.com/articles/31986]

AME Growth Needs Design & Layout

Merging of EDA & CAD

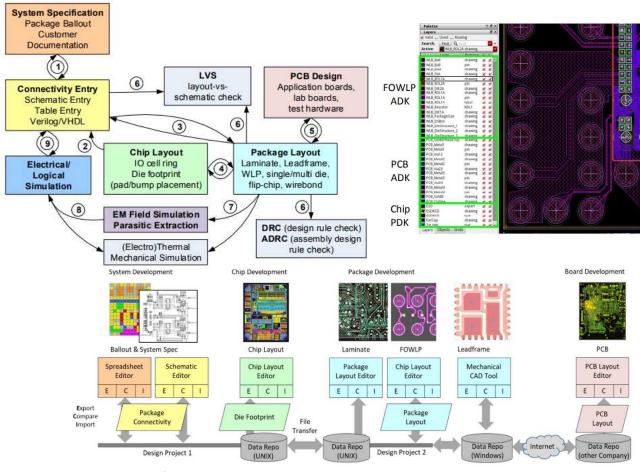
ModElec



[L. He, J. Wittkopf. Proc. ACM Interact. Mob. Wearable Ubiquitous Technol., Vol.5, No.4, Article159]

Integrated Co-Design Workflows

Example of Chip/Package/Board Co-design flow



DOI: <u>10.1109/ECTC32862.2020.00269</u>

AME Growth Needs Reliability

Product Testing Considerations

Thermal Cycling

Typical Tested Operating Temperature Ranges

Military -55°C to 125°C

Automotive -40°C to 125°C

Industrial -40°C to 85°C

AEC-Q100 Lvl 2 -40°C to 105°C

High Temp/High Humidity

Level 1 - 85°C/85%RH - 1000 hrs

Drop Analysis

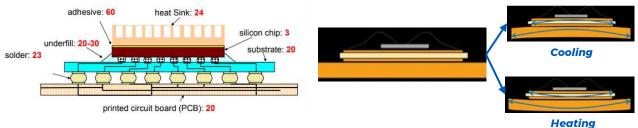
Per JESD22-B111A (2016)

Electromigration

Void & Hillock generation

Material CTE Considerations

CTE for Standard Packaging Materials ppm/°C

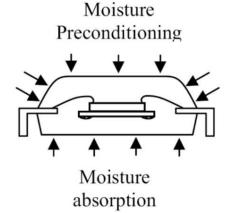


Ramdas, et al. (2019). Impact of Accelerated Thermal Aging on Thermo-Mechanical Properties of Oil-Immersed FR-4 Printed Circuit Boards.

Moisture Effects

Humid Environment Effects

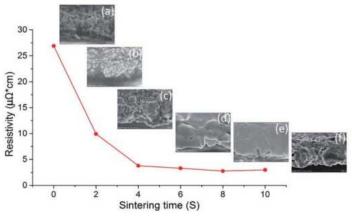
Material Swelling & Expansion Moisture Density enhancement Moisture Vaporization at Reflow Corrosion



https://doi.org/10.4233/uuid:9141f50e-5362-4b01-b06f-f1cc3acd6543

AME Growth Needs Material Properties

Conductor Properties



[W. Gu, W.Yuan, et al. RSC Adv., 2018,8, 30215-30222]

| Ink Type | Ink Composition | Conductivity $1.8 \times 10^3 \text{ S/m}$ $(5.03 \pm 0.05) \times 10^3 \text{ S/m}$ | | |
|------------------------|---|--|--|--|
| Carbon conductive ink | Carbon CNT | | | |
| Polymer conductive ink | PEDOT:PSS | $8.25 \times 10^3 \text{S/m}$ | | |
| Nano-silver ink | Ag-DDA Ag-PVP | $3.45 \times 10^7 \text{ S/m}$ $6.25 \times 10^6 \text{ S/m}$ | | |
| Liquid metal ink | EGaIn Bi ₃₅ In _{48.6} Sn ₁₆ Zn _{0.4} | $3.4 \times 10^6 \text{ S/m}$ $7.3 \times 10^6 \text{ S/m}$ | | |

doi:10.3390/mi7120206

Ag bulk conductivity 6.3E7 S/m **Cu bulk conductivity** 6.0E7 S/m

Dielectric Material Properties

Example - RDL Material Property Considerations

| Characteristic | Ideal Properties | Polymer Family | | | | | | | |
|----------------|--|----------------|-----|-----|-----------|------------------|---------|--------|-------------|
| | | Ероху | | DOD | Date: | Polybenz- | Fluro- | Hydro- | |
| | | Non PID | PID | BCB | Polyimide | oxozole (PBO) | polymer | carbon | Metal Oxide |
| Electrical | Low loss Low D _k | | | | | | | | |
| Physical | Ultra thin dry film (2-5 µm) Planar | | | | | | | | |
| Thermal | Low-CTE Withstand 260 °C solder reflow | | | | | | | | |
| Mechanical | High Elongation Low modulus | | | | | | | | |
| Chemical | Resistance to chemicals Good adhesion | | | | | | | | |
| Cost | Low Material and Processing Cost | | | | | | | | |
| Reliability | Low Stress Low moisture absorption | | | | | | | | |

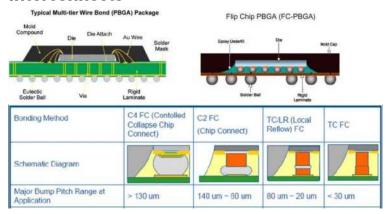
DOI 10.1109/ECTC32862.2020.00182

Both especially important for high-speed and high-frequency Applications!

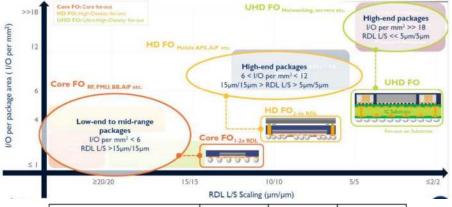
AME Growth Needs Application Targets

Advanced Packaging Targets

Interconnects



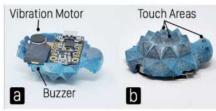
Redistribution Layers (RDL)



| | 2019 | 2023 | 2027 |
|-------------------------------------|------------|------------|------------|
| Link speed (Gbps)_Serial Speeds [4] | 50 | 100 | 200 |
| BU dielectrics loss, Df | 0.007 | 0.004 | 0.002 |
| BU dielectric roughness (Rq) | 300~400 nm | 150~200 nm | 100~150 nm |
| Cu roughness (Rq) | 350~400 nm | 200~250 nm | 50~100 nm |

[HIR 2021 version (eps.jeee.org/hir), Ch. 8 & Ch. 231

Application Targets Leveraging Unique AME Capabilities



[L. He, J. Wittkopf. Proc. ACM Interact. Mob. Wearable Ubiquitous Technol., Vol.5, No.4, Article159]



DOI: 10.29026/oea.2018.170004

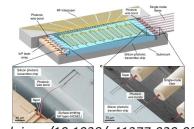
3D Form Factors



[https://www.jabil.com/blog/flexible-electronics.html]



DOI 10.1186/s13104-015-0971-9
Individualized Designs



doi.org/10.1038/s41377-020-0272-5 **Meeting Unique Needs**



https://doi. org/10.1038/s41563-018-0084-7

Flex/Stretch Electronics

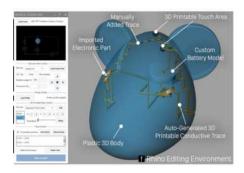
AME for Packaging & HI Impact



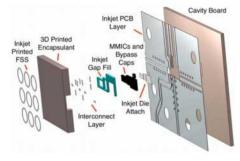
[M. Ankenbrand, M. Hedges. 2019 International Conference on Electronics Packaging (ICEP), 2019, pp. 273-278]



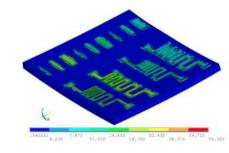
[H. Tan, C. Chua. Progress in Materials Science 127 (2022) 100945]



[L. He, J. Wittkopf. Proc. ACM Interact. Mob. Wearable Ubiquitous Technol., Vol.5, No.4, Article159]



[M. Tentzeris, et al. IEEE Trans Microwave Theory Tech., **2020**, 68, 2716-2724]



[https://doi.org/10.1016/ j.microrel.2018.04.008]

Manufacturing Methods & Integration

+ Materials

+

Design Tools

+

Application Development

System Reliability

Needing Concerted Advances from all for Adoption & Market Success